

Search Notes

Application/Control No.

10/767,767

Examiner

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Applicant(s)/Patent under
Reexamination

OGAWA, HIDEHIKO

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
358	1.15, 402, 440	11/22/2005	TDL
379	100.01	11/22/2005	TDL
379	100.08	11/22/2005	TDL
379	100.13	11/22/2005	TDL
379	100.17	11/22/2005	TDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR